

Silicon-Based Resonant Microsensors

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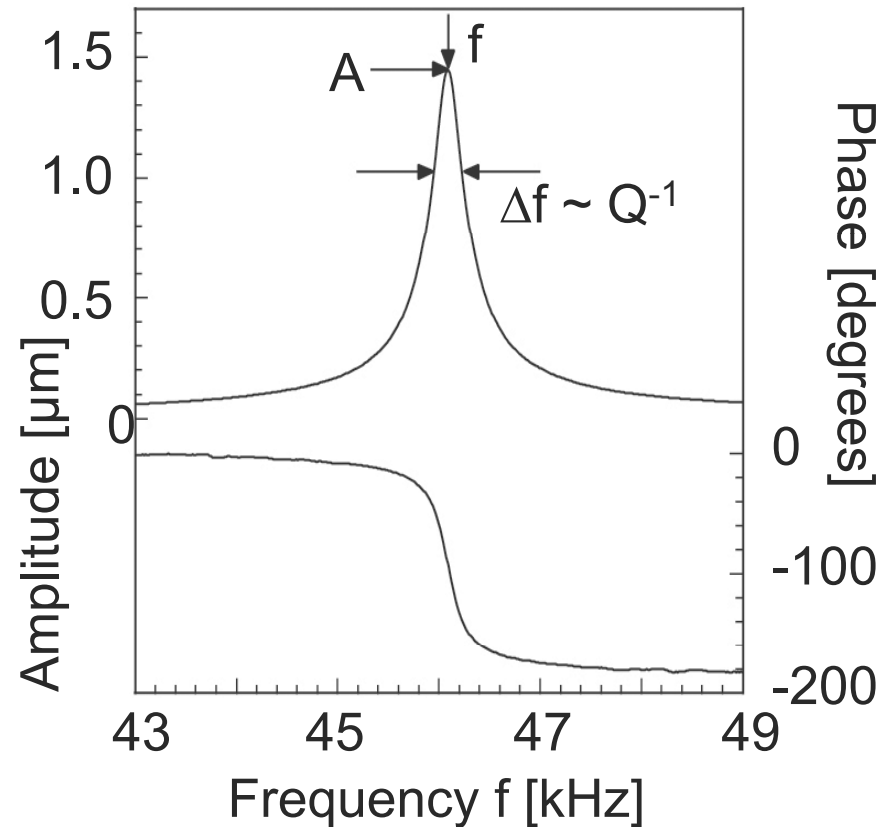
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<http://mst.ece.gatech.edu>

Outline

- Resonant Microsensors
 - Operation Principles and Applications
- Frequency-Output Sensors
 - Operation in Feedback Loop
 - “Device” vs. “System-Level” Resonant Sensor
 - Frequency Resolution and Drift
 - Drift Compensation Techniques
- (Bio)Chemical Resonant Microsensor Platform
 - Disk-Type Microstructure Optimization
 - Chemical Sensing
- Summary and Outlook

[Resonant Sensors]

- Measurand affects characteristic of resonant behavior of microstructure
 - **Resonance frequency**
 - Quality factor
 - Vibration amplitude
 - Phase



Resonant Sensors

Measurand = Input Signal

Acceleration
Angular Rate
Concentration
Deposition Rate
Flow
Fluid Density
Force/Torque
Humidity
Magnetic Field
Mass
Pressure
Radiation
Temperature
Viscosity
.....

*1. Signal
Conversion
(if required)*

Intermediate Signal

Damping
Driving Force
Force/Torque
Geometry
Mass
Material Properties

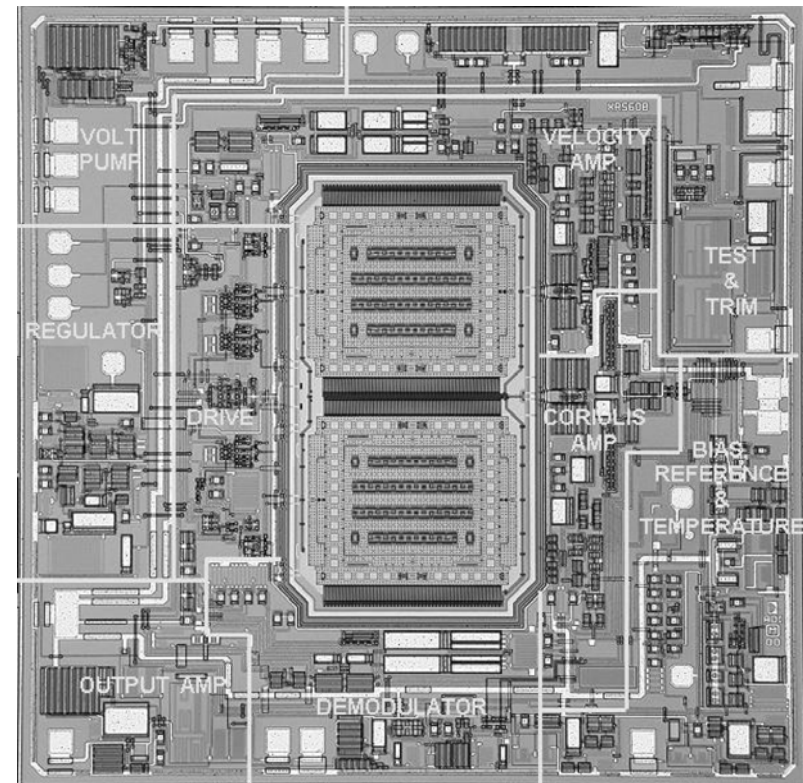
*2. Signal
Conversion
by
Resonant
Structure*

Output Signal

Frequency
Amplitude
Phase
Damping

Why Resonant Sensors?

- Resonant Sensors
 - Quasi-digital output signal
 - Frequencies can be measured precisely
- If Combined with CMOS Technology
 - Established fabrication base
 - On-chip circuitry
 - Fabrication outsourcing



Analog Devices ADXRS 150

Frequency-Output Sensors

– Working Principle –

$$m \frac{d^2x}{dt^2} + b \frac{dx}{dt} + kx = \sum F_i$$

■ Device-Level Frequency Sensor

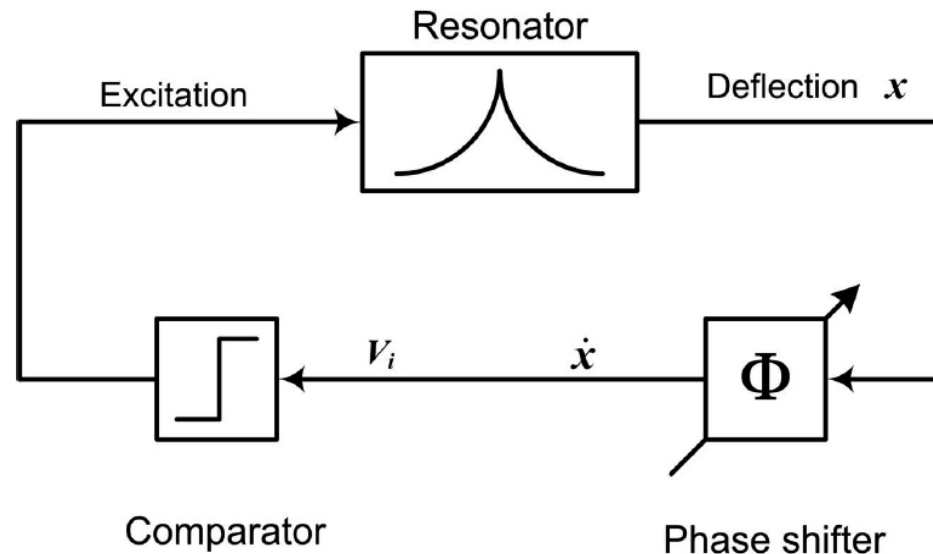
$$F = F_1 = b \frac{dx}{dt} \quad \Rightarrow \quad f = \frac{1}{2\pi} \sqrt{\frac{k}{m}} \quad \Rightarrow \quad \frac{\Delta f}{f} = \frac{1}{2} \left[\frac{\Delta k}{k} - \frac{\Delta m}{m} \right]$$

■ System-Level Frequency Sensor

$$F = F_1 + F_2 + F_3 = b \frac{dx}{dt} + k_{\text{add}} x + m_{\text{add}} \frac{d^2x}{dt^2} \quad \Rightarrow \quad f = \frac{1}{2\pi} \sqrt{\frac{k - k_{\text{add}}}{m - m_{\text{add}}}}$$

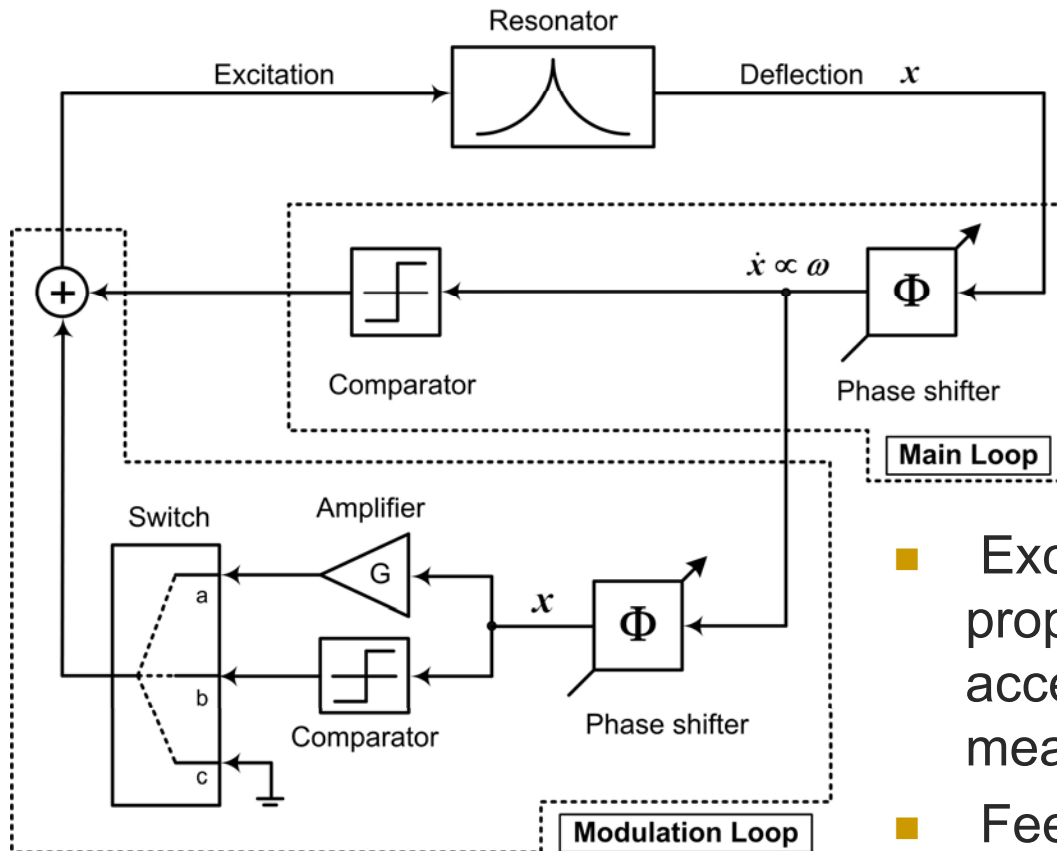
$$\frac{\Delta f}{f} = \frac{1}{2} \left[\frac{m_{\text{add}}}{m} - \frac{k_{\text{add}}}{k} \right]$$

Device-Level Frequency Sensor



- In steady state, the excitation force compensates for damping loss and microstructure vibrates with constant amplitude
- Changes of the effective spring constant or mass result in a measurable frequency change

System-Level Frequency Sensor



- Excitation force component proportional to deflection (or acceleration) is modulated by measurand
- Feedback loop introduces measurable frequency change

Resonant Magnetic Field Sensor

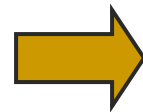
– Working Principle –

- Current through coil $I = k_B x$ generates Lorentz force F_L proportional to the cantilever deflection x in presence of magnetic field

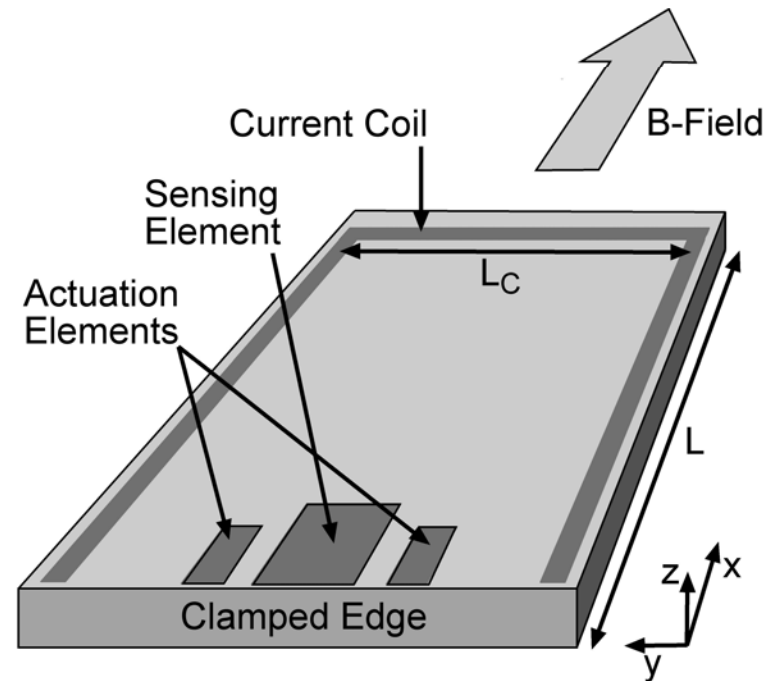
$$F_L = q(v \times B) = IL_C B = k_B x L_C B$$

- Assume: resonator damping compensated by thermal bimorph actuation

$$m \frac{d^2 x}{dt^2} = -kx + F_L = (k_B L_C B - k)x$$

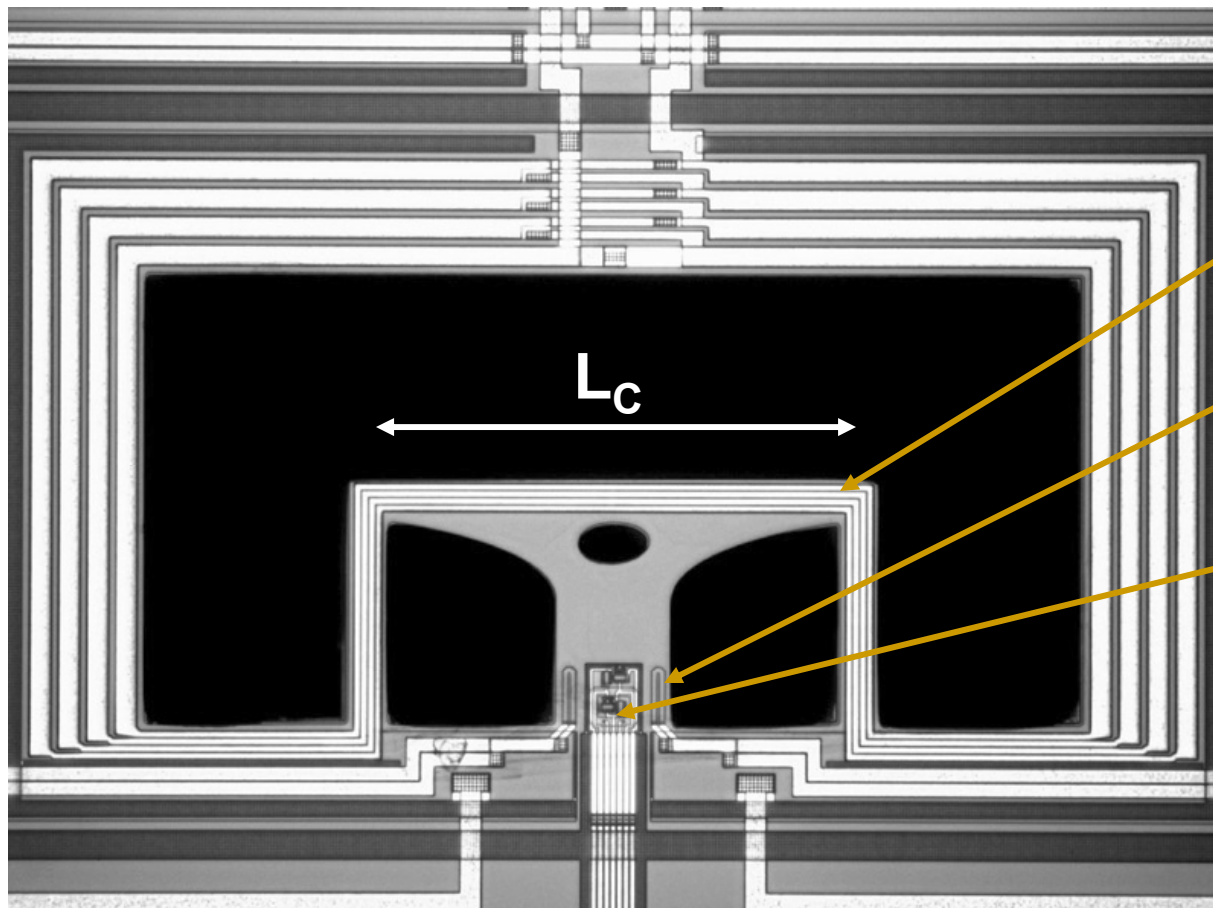


$$f = \frac{1}{2\pi} \sqrt{\frac{k}{m}} = \frac{1}{2\pi} \sqrt{\frac{k - k_B L_C B}{m}}$$



Resonant Magnetic Field Sensor

– Microstructure Design –



Coil

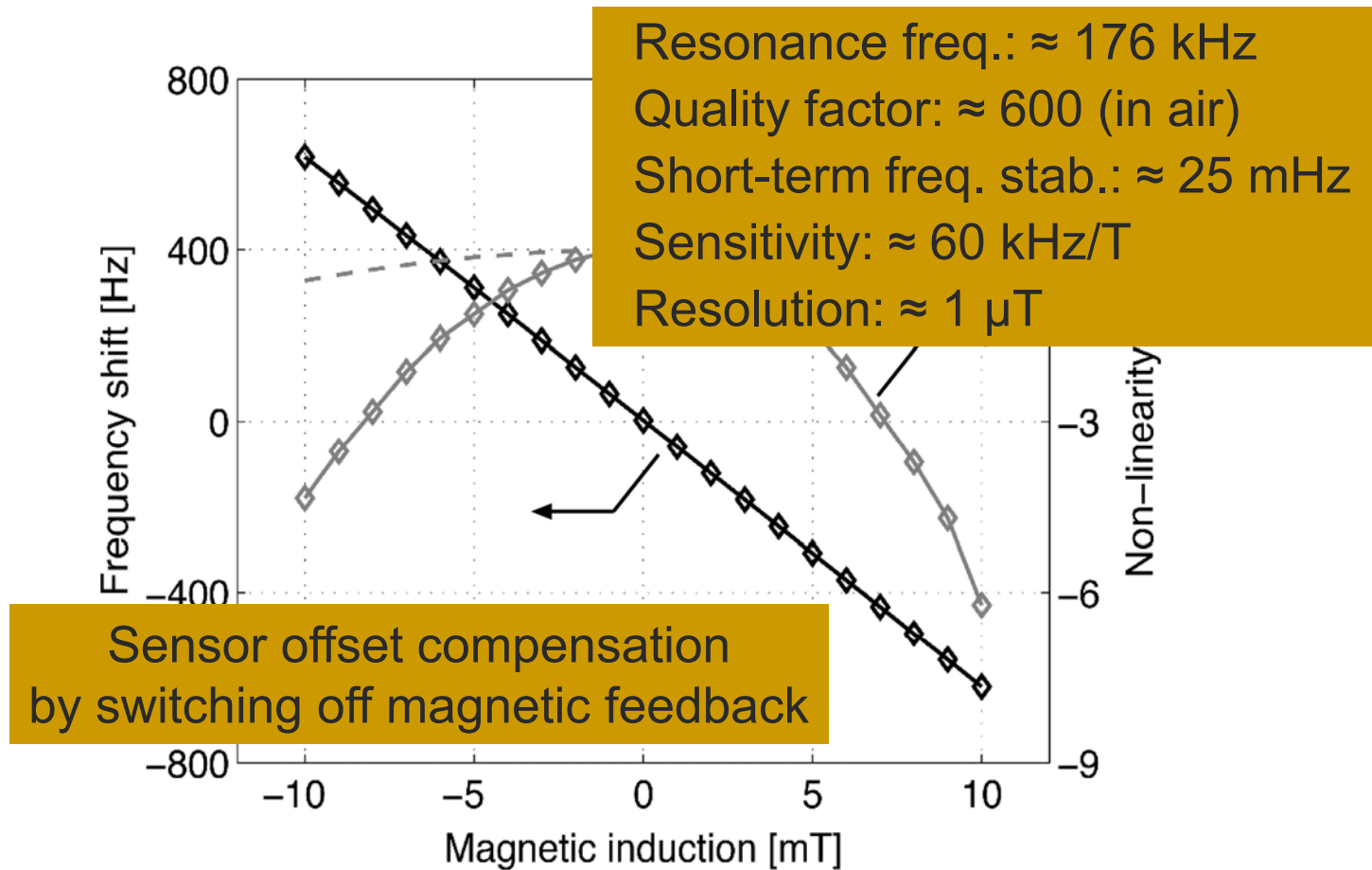
Thermal
Actuator

Wheatstone
Bridge

R. Sunier et al.,
IEEE J. MEMS,
15 (2006) 1098-1107

Magnetic Field Detection

– Sensor Sensitivity –



Resonant Sensor Resolution

- **Sensor resolution** is limited by sensor sensitivity S [Hz/"measurand change"] and minimal detectable frequency change Δf_{\min} [Hz]

$$C_{\min} = \frac{\Delta f_{\min}}{S}$$

- **Limit of Detection (LOD)** is measurand amplitude that generates three times the noise amplitude, i.e.

$$\text{LOD} = 3 \frac{\Delta f_{\min}}{S}$$

- Minimizing Δf_{\min} generally demands maximizing quality factor Q ; e.g. for cantilever in amplifying feedback loop

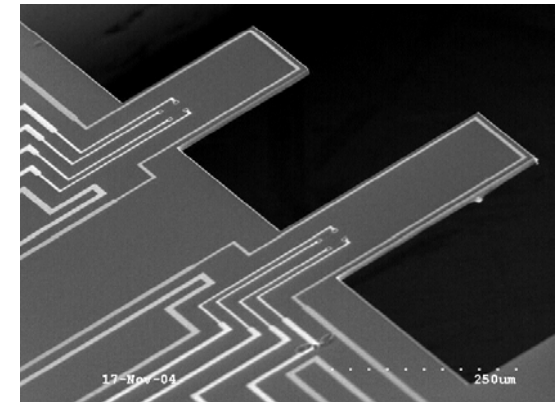
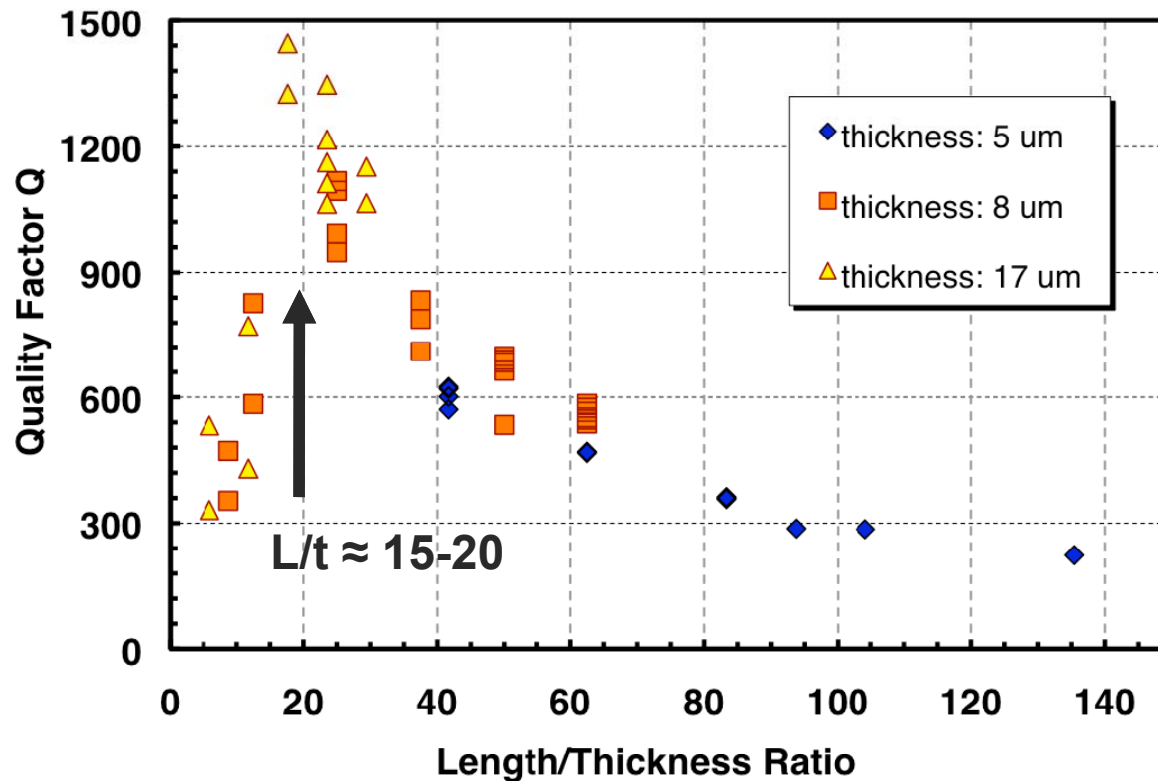
$$\Delta f_{\min} = \sqrt{\frac{f_0 k_B T B}{2\pi k Q \langle x^2 \rangle}}$$

Albrecht et al.,
J. Appl. Phys. **69** (1991) 668

Silicon Cantilever Beam

– Q-Factor Optimization –

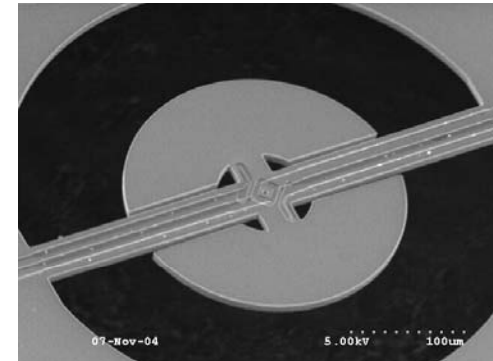
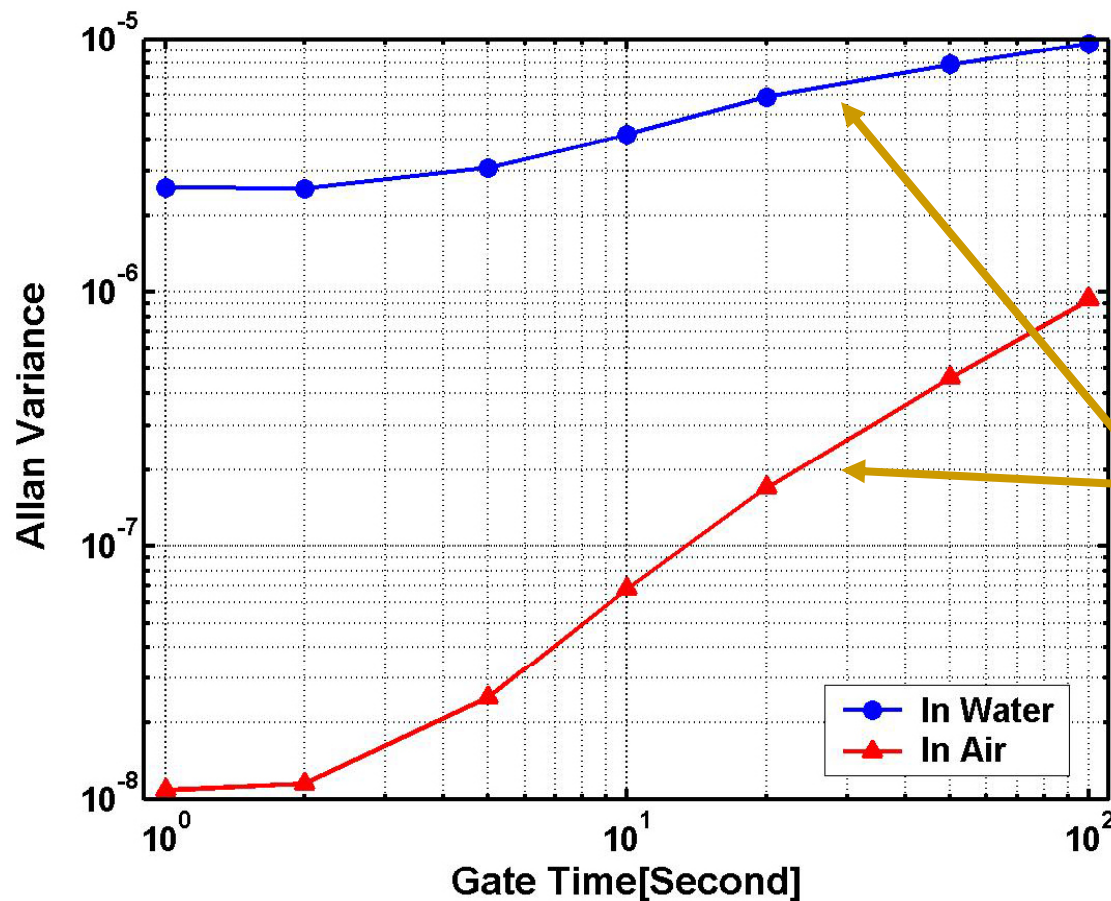
Support loss Air damping



K. Naeli et al.,
Proc. Transducers '07,
pp. 245-248

Silicon Disk-Resonators

– Allan Variance vs. Gate Time –



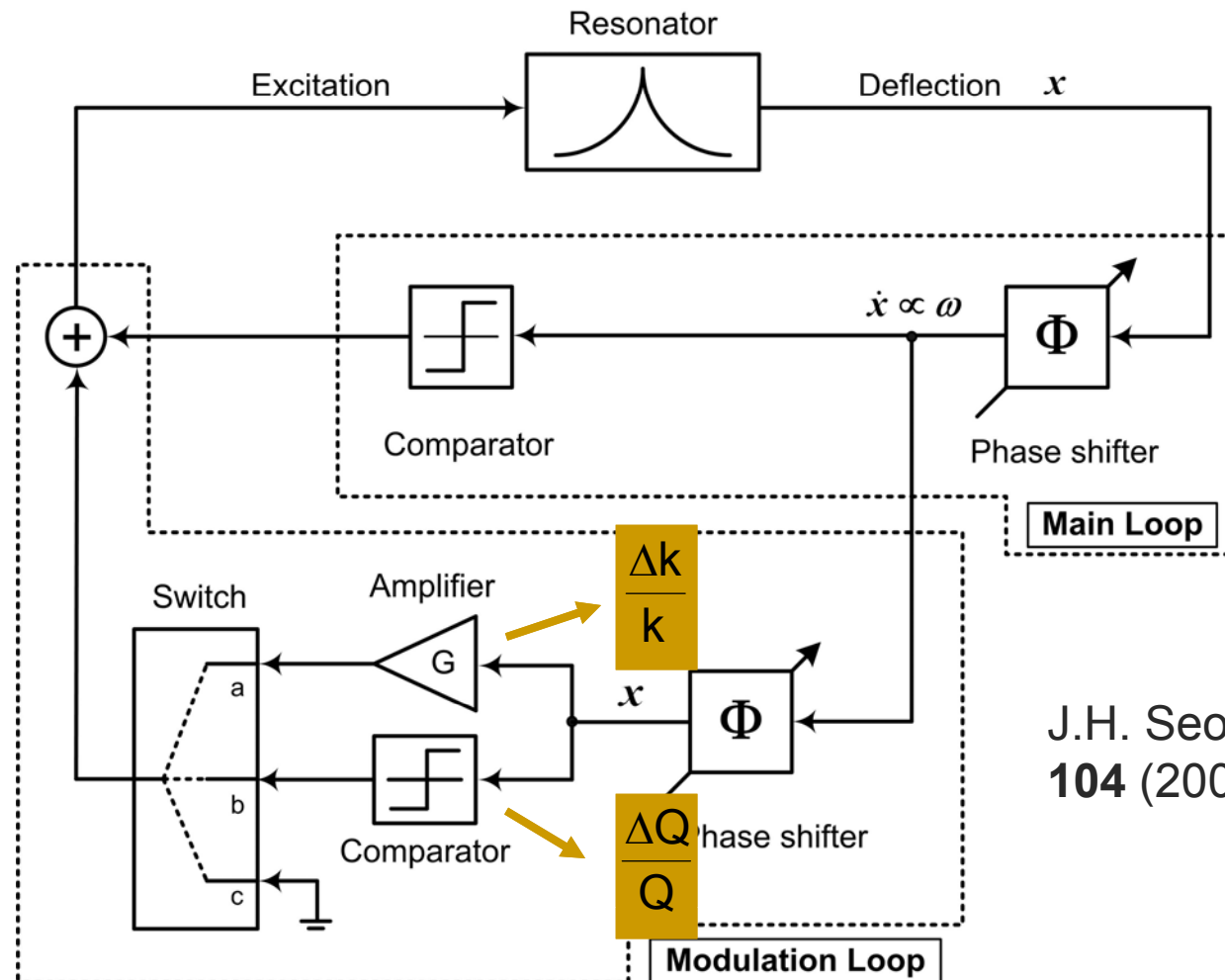
Increase due to Long-Term Drift

$$\sigma^2(\tau, m) = \frac{1}{2m} \sum_{n=1}^m (\gamma_{n+1} - \gamma_n)^2$$

$$\gamma_n = \frac{f_{n+1} - f_n}{f_n}$$

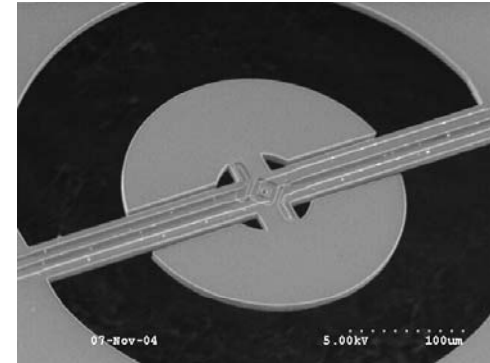
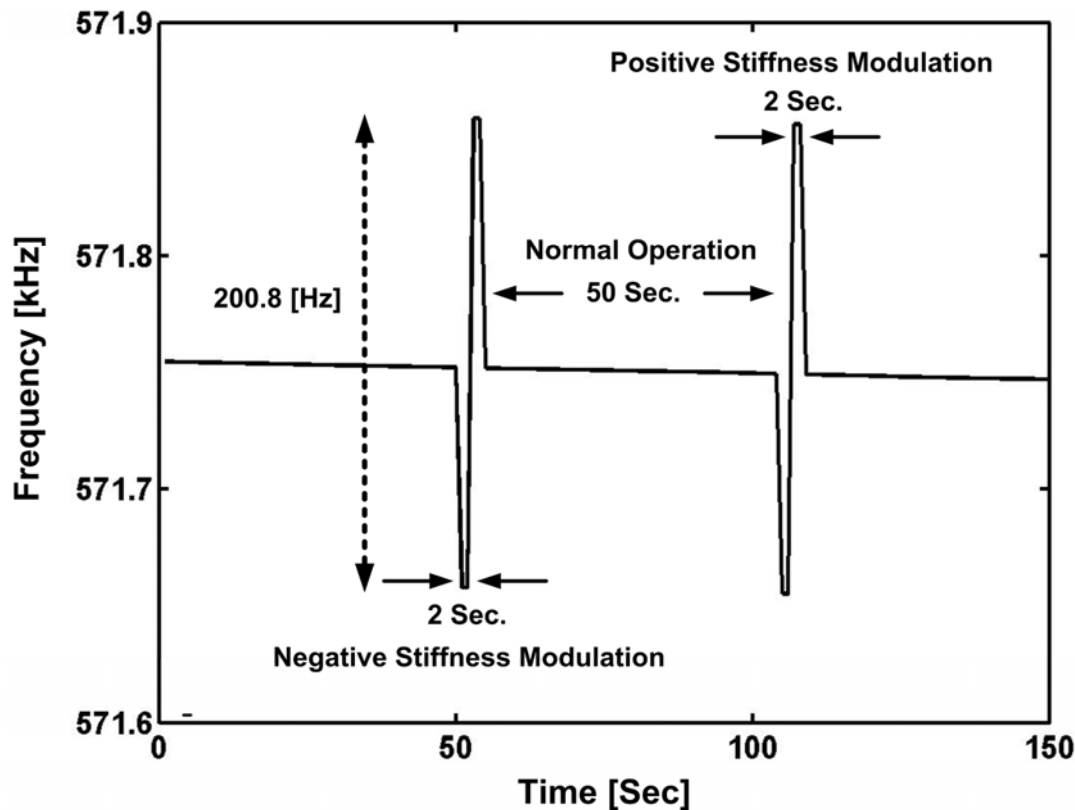
Drift Compensation: Method I

– Controlled Stiffness Modulation –



J.H. Seo et al., *J. Appl. Phys.*
104 (2008) 014911

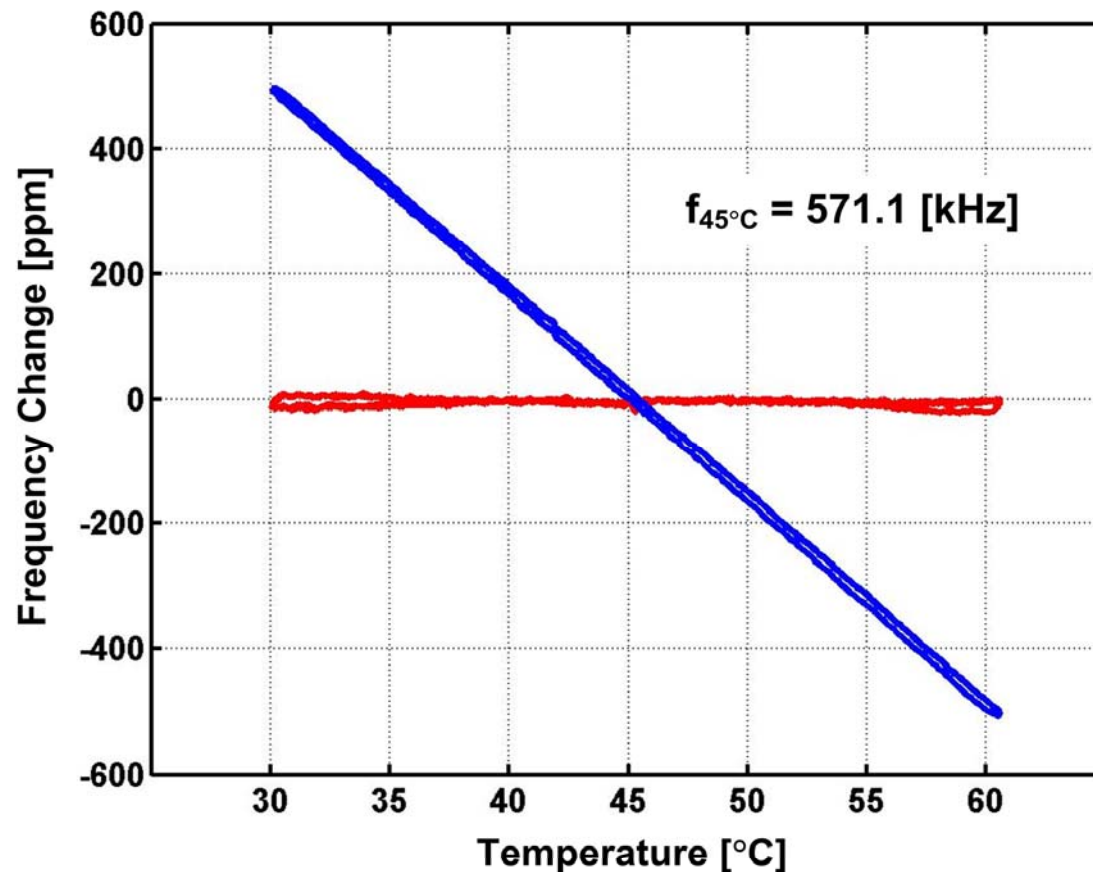
Q-Factor Tracking via Periodic Stiffness Modulation



$$\left(\frac{\omega_{\text{POS}}}{\omega_{\text{NEG}}} \right)^2 = \alpha$$

$$Q = \frac{\alpha + 1}{\alpha - 1}$$

Temperature Compensation via Q-factor Tracking



Uncompensated:

$$df/dT \approx -33 \text{ ppm/}^{\circ}\text{C}$$

Compensated:

$$df/dT < 2 \text{ ppm/}^{\circ}\text{C}$$

J.H. Seo et al,
Proc. Hilton Head Workshop,
pp. 190-193, 2008

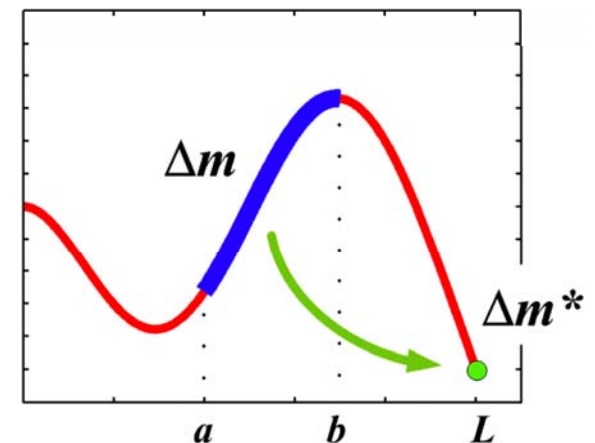
Drift Compensation: Method II

– Overtone Analysis in Prismatic Beams –

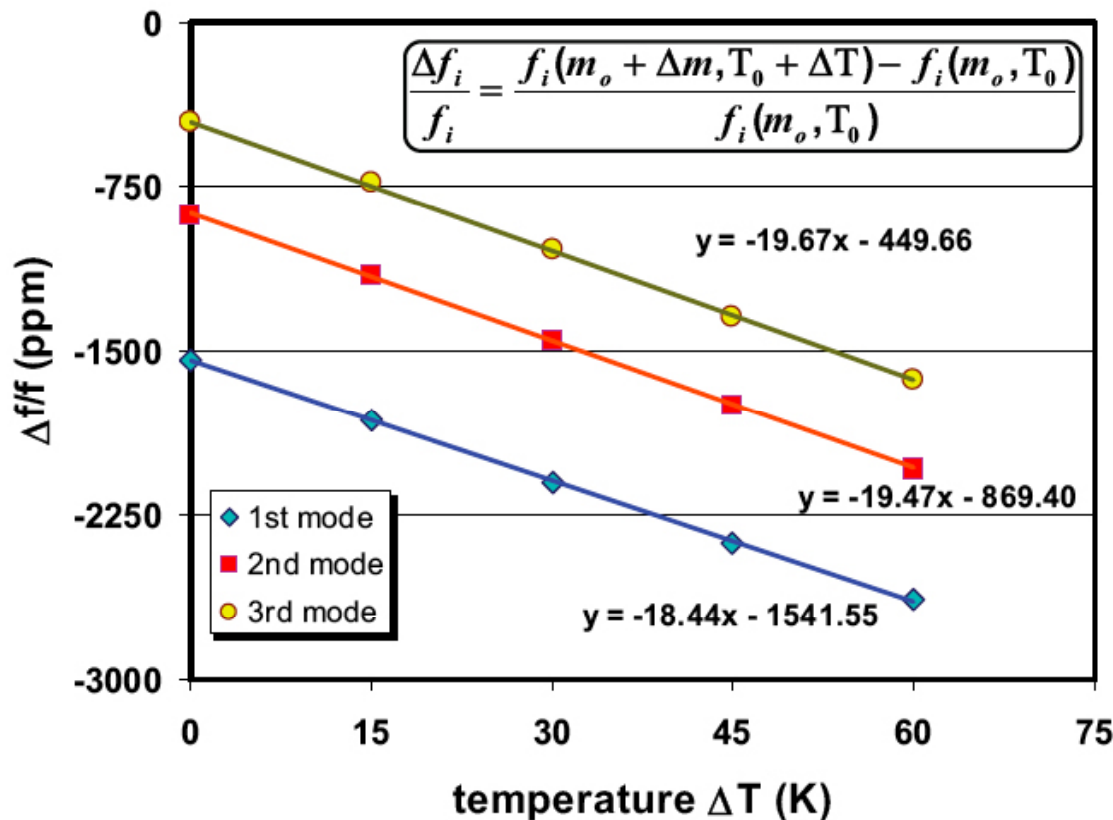
- Goal: Compensation for environmental effects in cantilever-based mass-sensitive sensors
- Idea: Explore flexural resonances of **partly-covered** beams
- Key: Flexural resonance frequencies of prismatic, homogeneous beam only differ by L_i

$$f_i = \frac{\lambda_i^2}{2\pi\sqrt{12}} \frac{t}{L^2} \sqrt{\frac{E}{\rho}}$$

- Assumption: added mass does not affect k !
- **Difference of relative frequency changes $\Delta f_i/f_i - \Delta f_j/f_j$ only depends on added mass but NOT on environmental changes!**

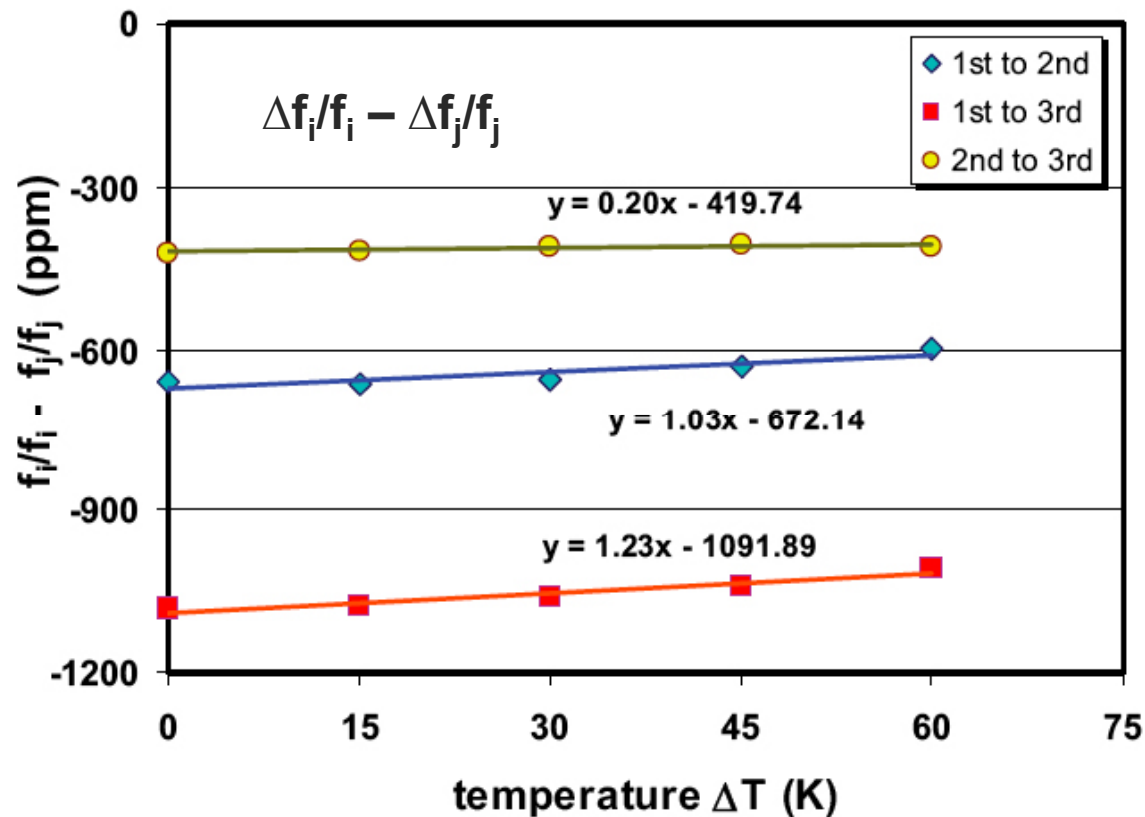


Temperature Compensation via Overtone Analysis



O. Brand, K. Naeli et al.,
Proc. MME 2008 Workshop,
pp. 121-127, 2008

Temperature Compensation via Overtone Analysis



Uncompensated:

$$df/dT \approx -20 \text{ ppm/}^\circ\text{C}$$

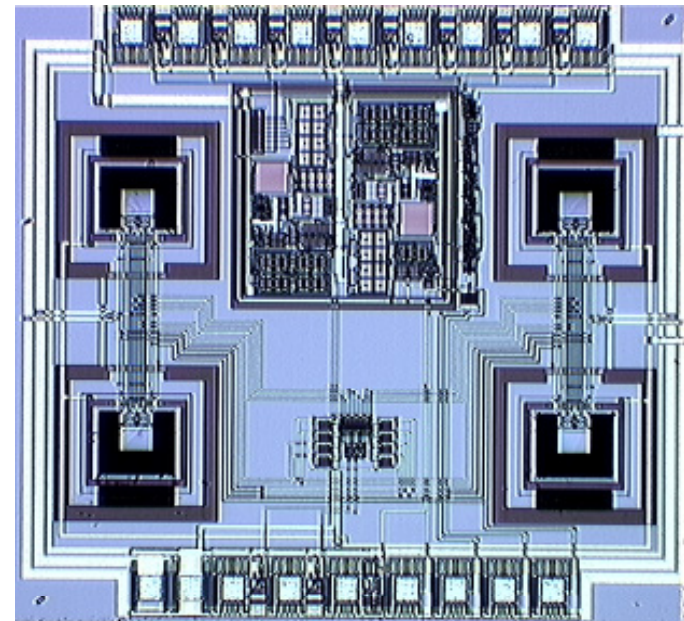
Compensated:

$$df/dT \approx 0.2 \text{ ppm/}^\circ\text{C}$$

O. Brand, K. Naeli et al.,
Proc. MME 2008 Workshop,
pp. 121-127, 2008

Resonant BioChemical Sensors

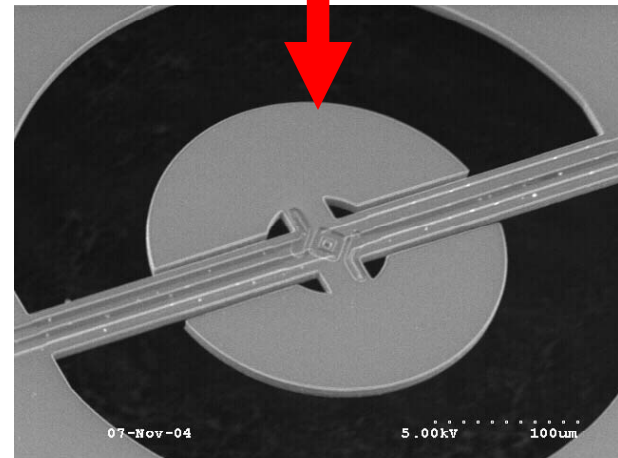
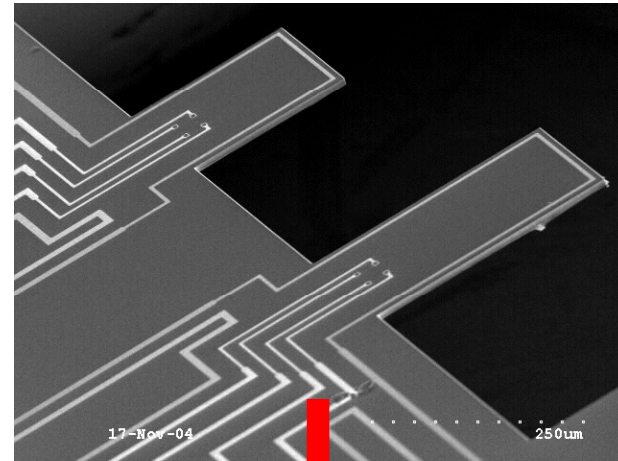
- **Approach:** Recognition film deposited onto microresonator ad-/absorbs analyte, thus lowering the microstructure's resonance frequency
 - **Implementations:** Acoustic wave devices, tuning forks, cantilevers
 - **Applications:** Chemical safety, surveillance applications, environmental monitoring, medical diagnosis
- ➔ **Sensor Arrays:** Sensor selectivity through sensor arrays coated with different recognition films



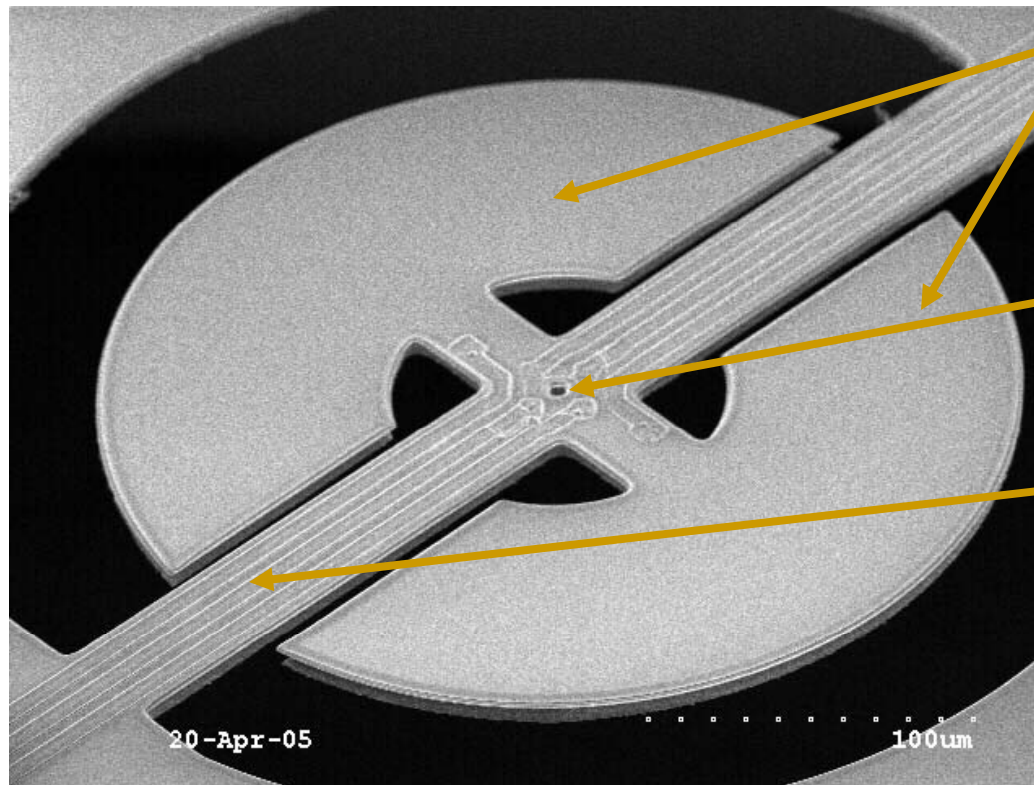
D. Lange et al.,
Anal. Chem. **74** (2002) 3084-3095

Resonant Sensor Platform for BioChemical Sensing

- **Goal:** Develop mass-sensitive sensor platform for biochemical applications **in air/liquid**
 - Large sensing area
 - High Q-factor
 - Dynamic instead of static sensing principle
- **Approach:** Investigate in-plane (instead of out-of-plane) vibration modes to improve Q-factor
- Performance achieved so far:
 $Q \approx 5800$ in air at $f \approx 620$ kHz



[Disk-Shape Resonator]



Semi-discs to
be coated with
sensitive layer

Center of rotation
with sensing/actuation
elements

Support beam

Frequency $\approx 400\text{-}600$ kHz
Sensitivity ≈ 1 Hz/pg

J.H. Seo, O. Brand, *IEEE J. of MEMS* **17** (2008) 483-493

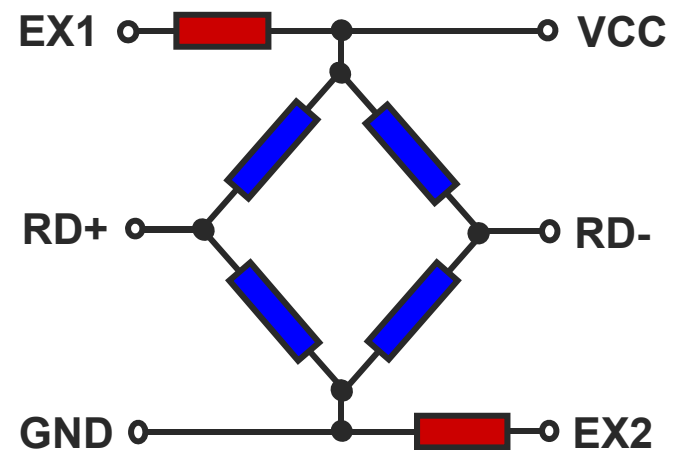
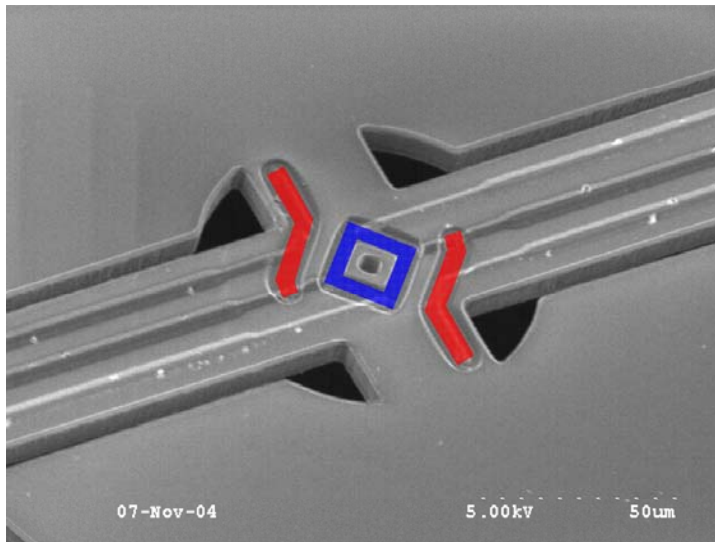
Driving and Sensing Structure

Thermal Actuation

- ⇒ Asymmetric arrangement of two heating resistors
- ⇒ Thermal expansion coefficient difference of Al and Si

Piezoresistive Sensing

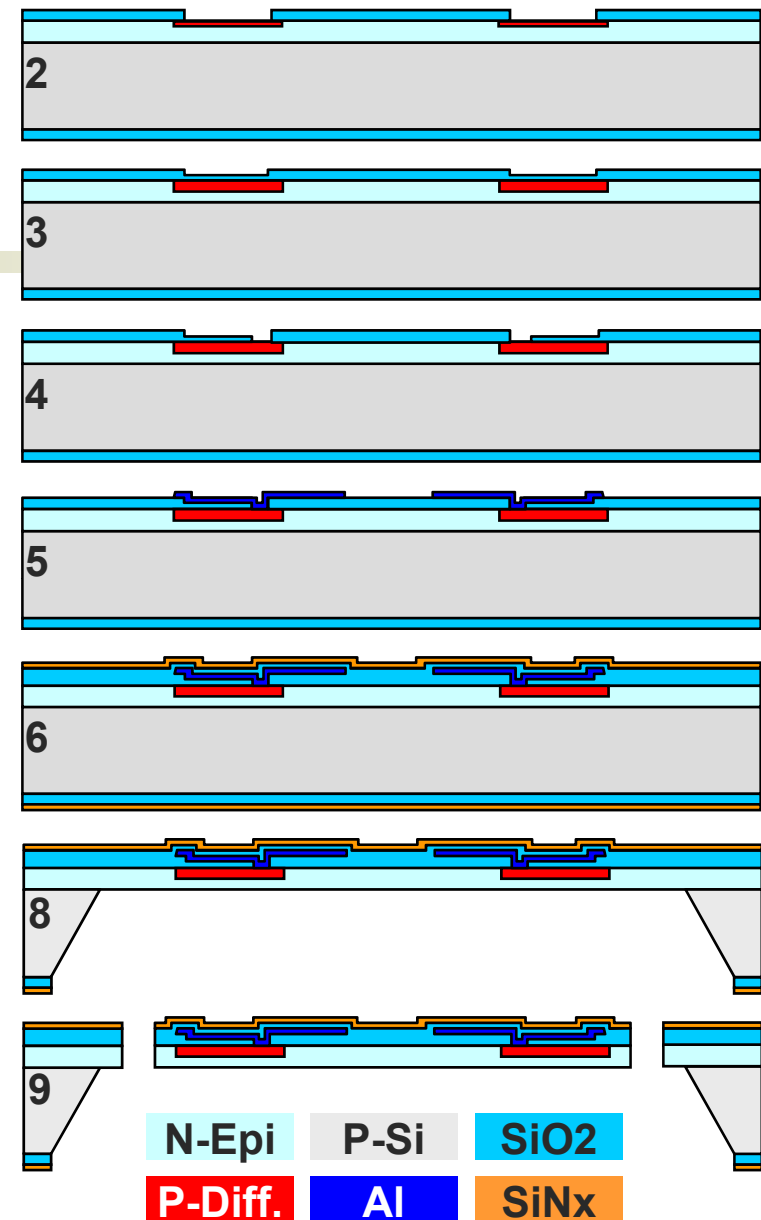
- ⇒ Wheatstone bridge sensitive only to desired in-plane vibration mode



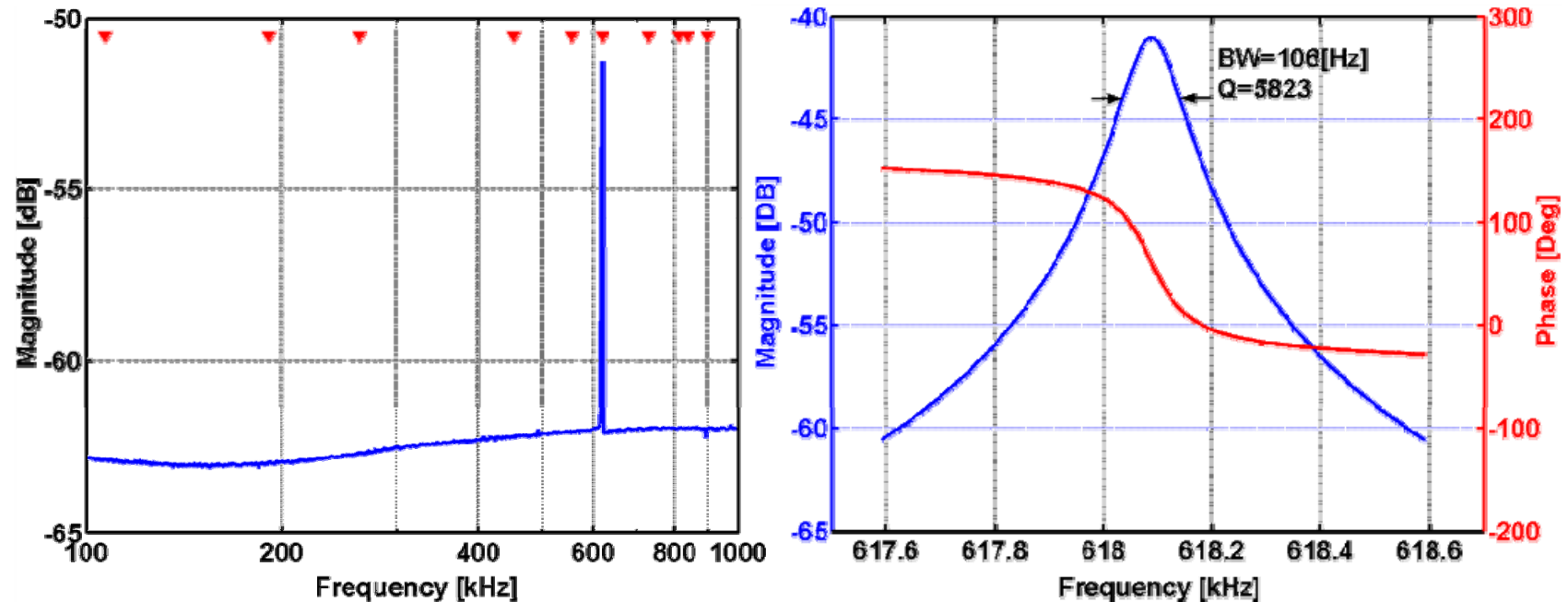
[Fabrication Flow

Substrate : Epi-wafer (5-10 μm n-layer)

1. Wet thermal oxidation
2. Pattern oxide & boron diffusion
3. Thermal oxidation
(Drive-in & oxidation)
4. RIE etching of contact openings
5. DC sputter & pattern Al
6. PECVD oxide & nitride deposition
7. Pattern back side nitride & oxide layer
8. Anisotropic KOH etch
9. Release structure with RIE

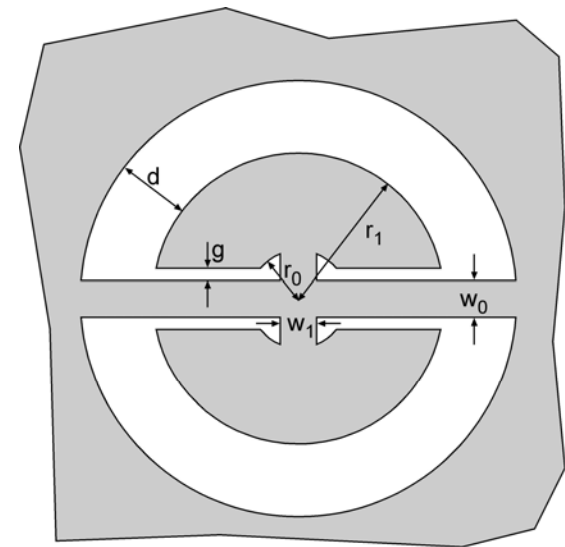
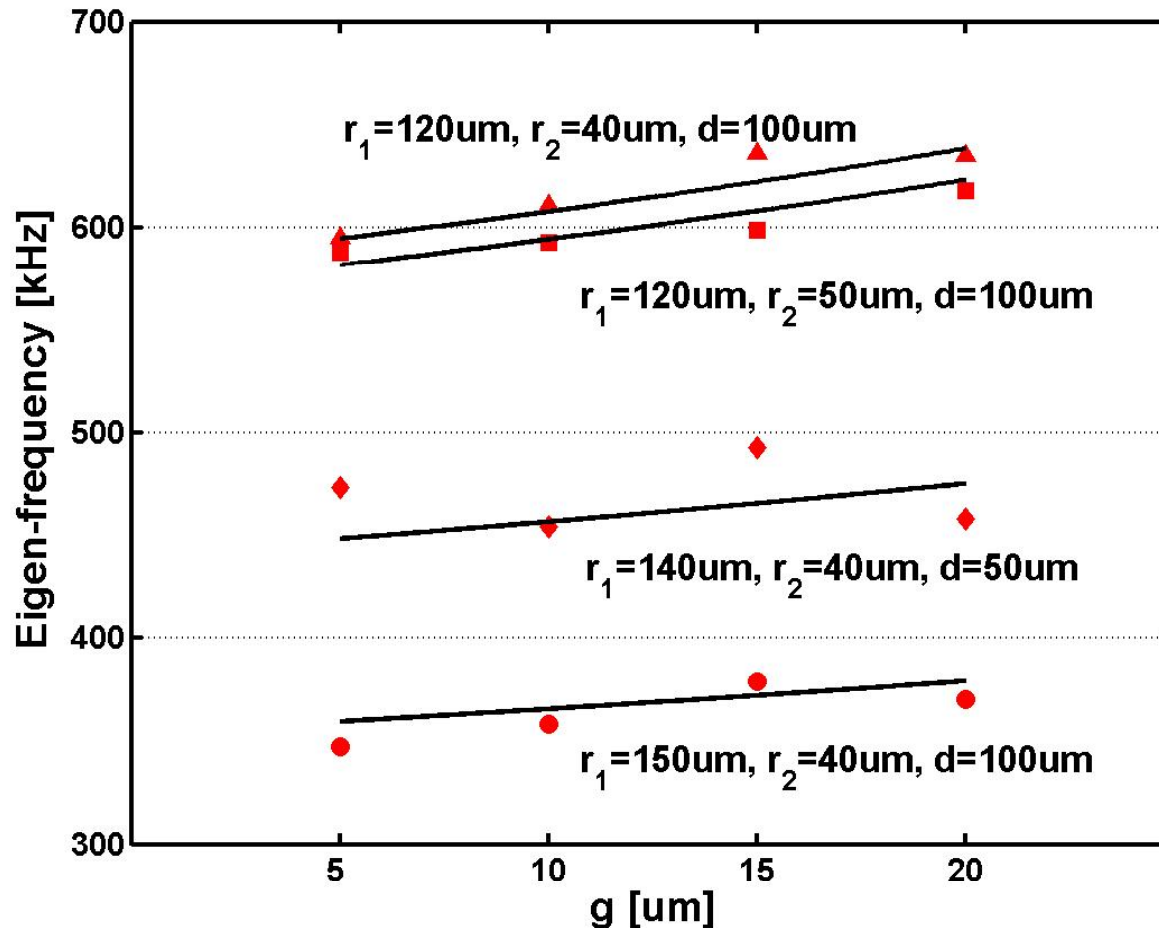


Transfer Characteristic



Quality factor in air up to 5,800; in water up to 100

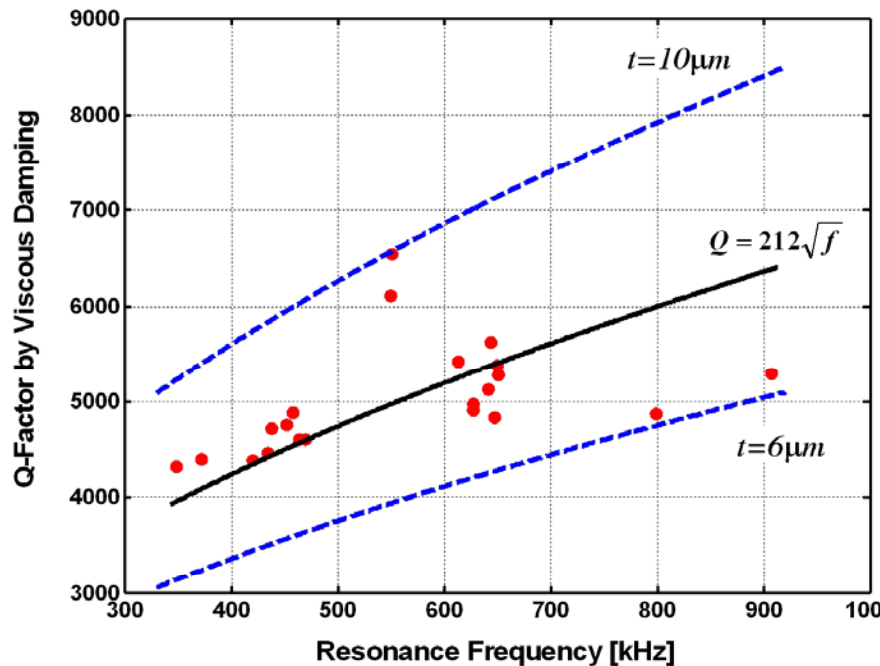
Resonance Frequency



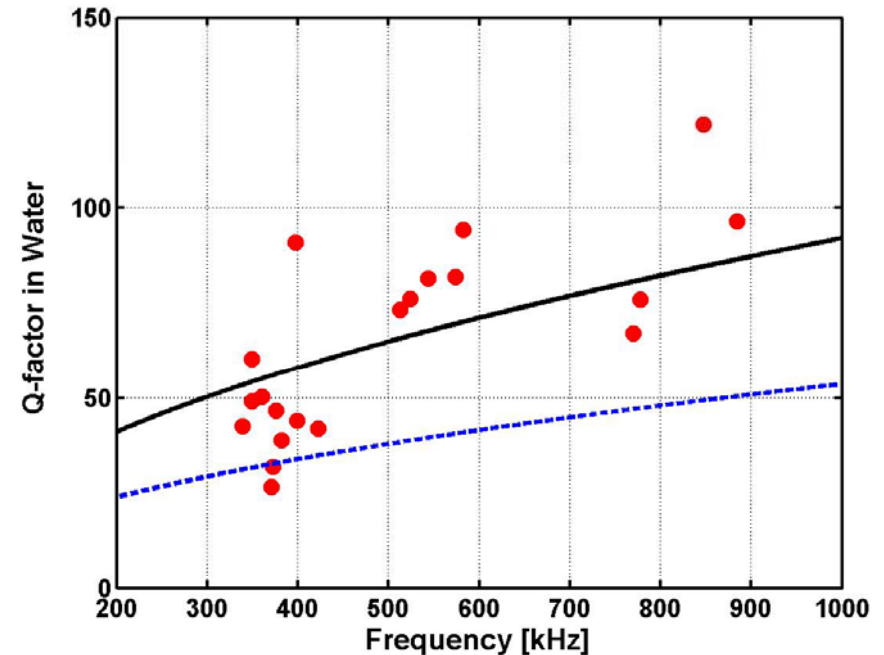
J.H. Seo, O. Brand,
IEEE J. of MEMS
 17 (2008) 483-493

Quality Factors in Air & Water

AIR



WATER



$$Q = \sqrt{\frac{\omega_0}{2 \nu}} \frac{\rho}{\rho_{\text{fluid}}} t$$

[Sensitive Layer Coating]

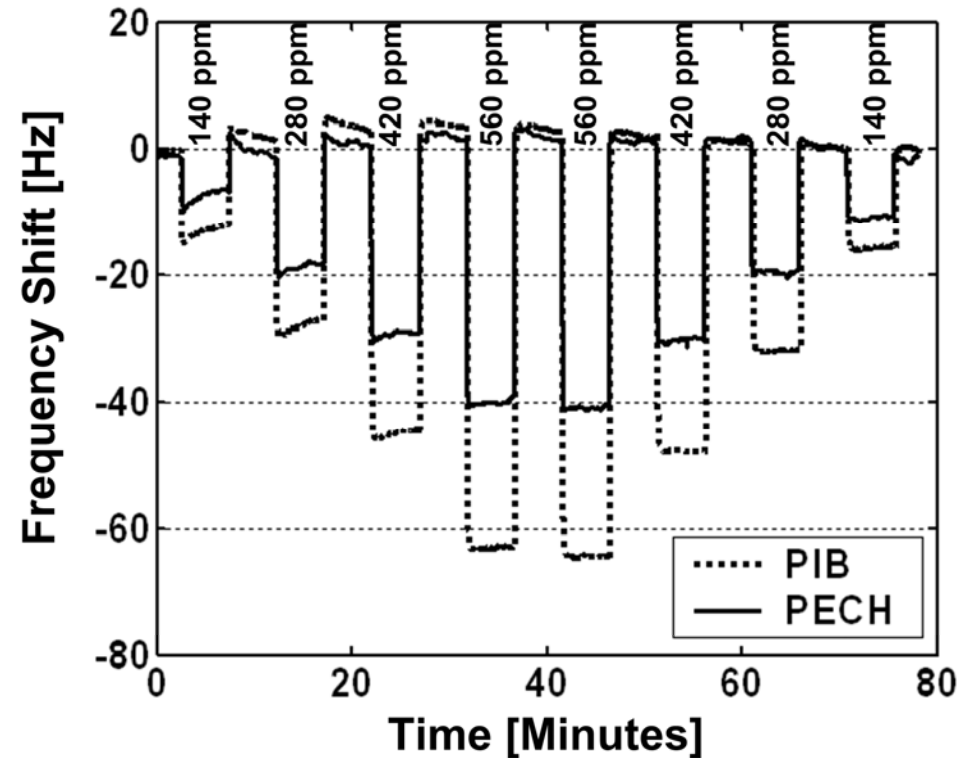
- Polymers for VOC enrichment
 - PIB: poly(isobutylene)
 - PECH: poly(epichlorohydrin)
- Polymer coating techniques
 - **Drop Coating:**
Dispensing from syringe or BioForce Nano eNabler
 - **Spray Coating:**
Dispensing with spray gun
- Polymer film thickness
 - 2-5 μm in air
 - $< 1 \mu\text{m}$ in water



*Disk resonator drop-coated
with polymer film*

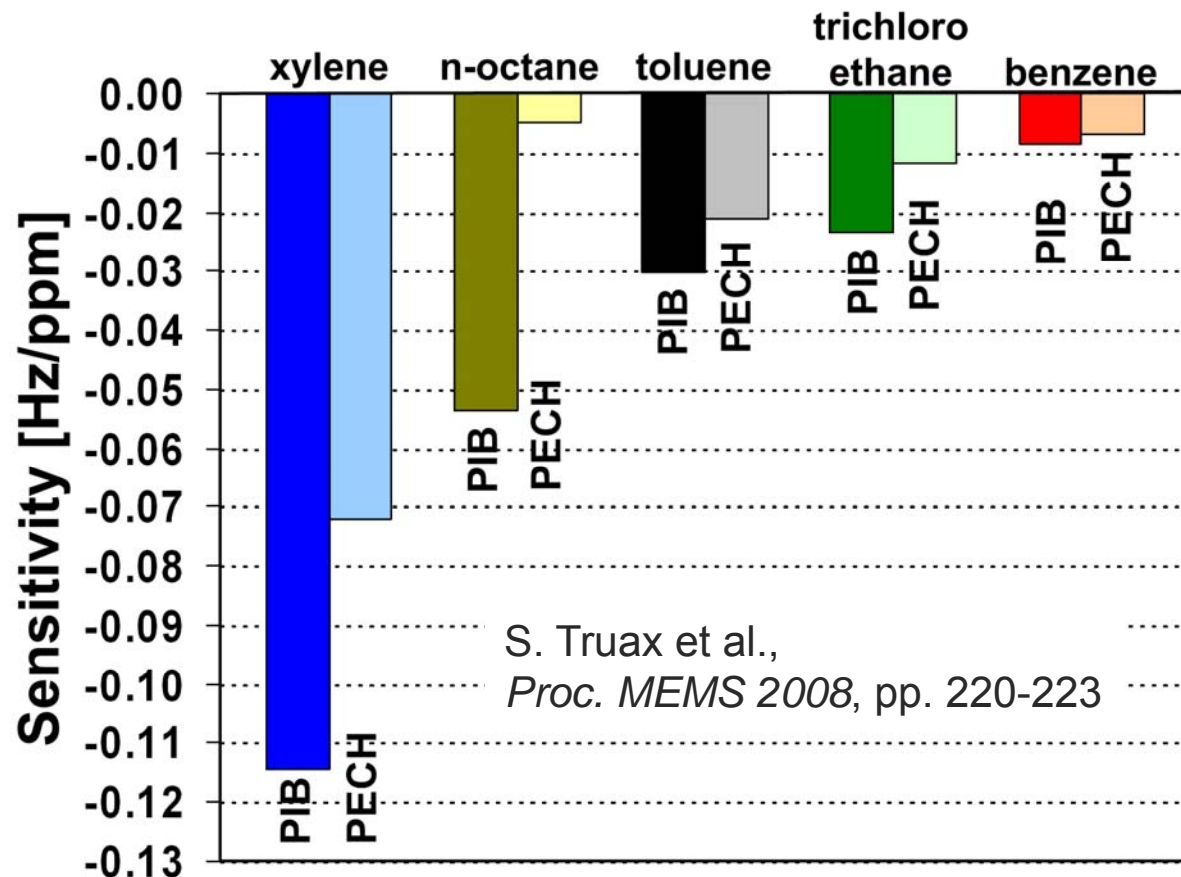
Gas-Phase VOC Sensing

- Exposure to different concentrations of o-xylene
- 4 μm spray-coated polymer films
- Turn-on and turn-off transients < 5 sec
- Short-term frequency stability ≈ 80 mHz (at 710 kHz & $Q = 940$)
- LOD ≈ 2 ppm for PIB/o-xylene



S. Truax et al., *Proc. MEMS 2008*, pp. 220-223

Sensitivities in Gas Phase



[Summary & Outlook]

- Resonant Microsensors
 - Benefit from wide applicability and (potentially) excellent resolution
 - Frequency modulation can be introduced on “device” or “system”-level
 - Effective methods for compensating long-term drift are essential and available
- Resonant Chemical Microsystem
 - Demonstrated Q up to 5,800 in air and 100 in water
 - Demonstrated gas (and liquid-phase) chemical sensing with ppm resolution
 - Demonstrated drift compensation via controlled stiffness modulation

Acknowledgements

